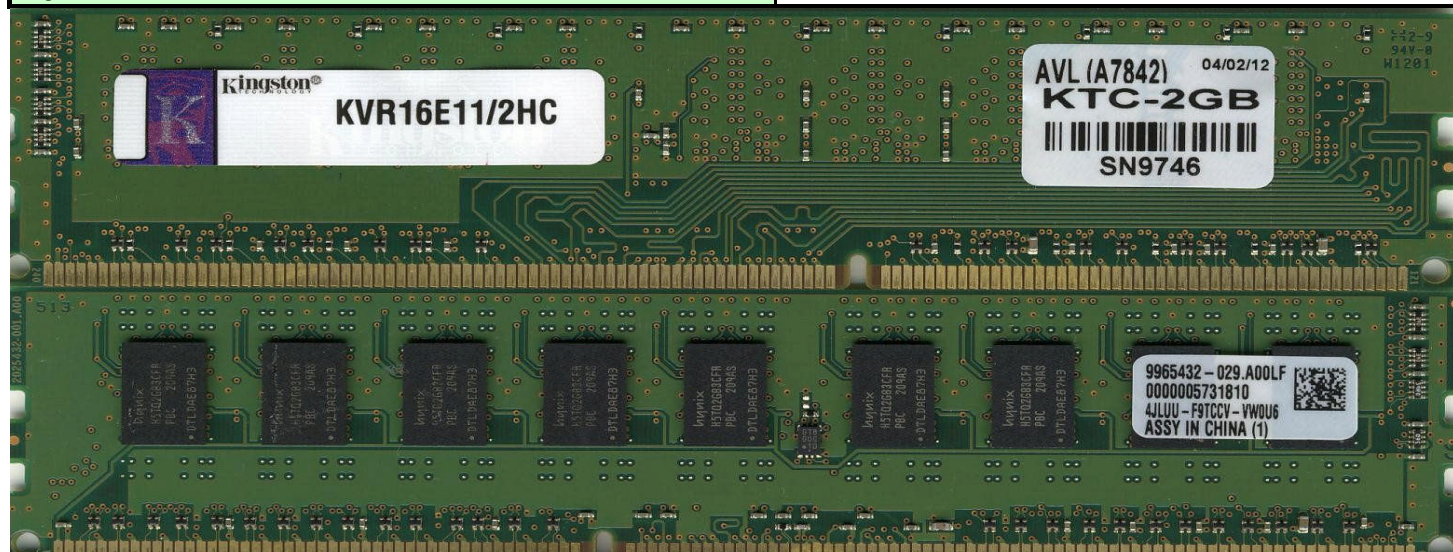


	AVL Supermicro server platform Memory Module Qualification Test		
	Intel E5-2650(SNB-EP) x 2, Intel C602	Test Results	Pass
	PN: KVR16E11/2HC (2GB / UDIMM ECC / ECC) On: X9DAI Rev.0		

RP77D3x-106-KI-SQ-SMC-V1		Module Information		Rev 01/07/2011
AVL WorkOrder #	wc3369	AVL A#	7842	
Start Date	4/18/2012	End Date	4/20/2012	
Tested By		Van N.		
Module Manufacturer		Kingston		
Module Part Number		KVR16E11/2HC		
Module BOM Number		9965432-029.A00LF		
Module Capacity / Memory Type / ECC		2GB / UDIMM EC(/ ECC		
Module Configuration (Width, # of devices, # of Ranks)		256Mx72 /9 Devices / 1 Rank		
Speed Tested (Data rate of Mbps, CL-tRP-tRCD)		DDR3-1600 /11-11-11/		
DRAM Device Vendor		Hynix		
DRAM Device Part Number / Date code		H5TQ2G83CFR-PBC		1209
DRAM Die Revision / Process Technology (nm)		C		
DRAM Device Config (Density / Width)		2Gbit / x8 / 256Mx8bit		
Thermal Sensor Device Vendor / Part Number / Revision		N/A		
Register Device Vendor / Part Number / Revision		N/A		



Platform System Information				
Motherboard Info (Model# & MB Revision & MB S/N & AVL S/N)	X9DAI	0	0	SN9376
BIOS Revision / BIOS Date	1	2/3/2012		
CPU / Speed	Intel E5-2650(SNB-EP) x 2		2.0GHz	
Chipset info (Stepping)	Intel C602			

	AVL Supermicro server platform Memory Module Qualification Test			
	Intel E5-2650(SNB-EP) x 2, Intel C602 PN: KVR16E11/2HC (2GB / UDIMM ECC / ECC) On: X9DAI Rev.0			

Test Results:	PASS
<i>Comments:</i>	

AVL Memory Module Qual Test Results Summary

Test # and name	Test Description	Specs	Test Results	Comments
1. Latest BIOS Upgrade & Configuration	Download / Upgrade latest BIOS & record size and speed detection		Done	
2. SPD Check	Memory module SPD content check for JEDEC compliance	JEDEC	Pass	Use proprietary tools
3. Reset Cycle	Run Linux based diags & utility software @ 50°C	50 loops	Pass	1 DIMM Per Channel when applicable
4a. Stress Application Test	Run Linux based diags & utility software @50°C	8 Hour per config	Pass	DIMM Loading per spec
4b. Stream Benchmark Test		5 loop per config	Pass	DIMM Loading per spec
4b. Reset Cycle		200 loop per config	Pass	DIMM Loading per spec
5. Functional Stress Test	Memory Stress Test @50°C -	12hrs	Pass	DIMM Loading per spec
6. Stress Application Test	Run Linux based diags & utility software @50°C	6hrs	N/A	3 DIMM Per Channel when applicable

Note: All test under IMC Vdd=Nom, Vref=Vddnom/2